Search Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/638,421	OCHI ET AL.
Examiner	Art Unit
Tu X. Nguyen	2618

	SEARCHED				
Class	Subclass	Date	Examiner		
455	7,11.1	6/6/2007	TN		
	13.1				
	16				
	511				
	423				
	15				
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
11.1	6/6/2007	TN		
15				
	11.1	11.1 6/6/2007		

SEAF (INCLUDING S	RCH NOT SEARCH S	ES STRATEGY)
		DATE	EXMR
Search East		6/6/2007	TN
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